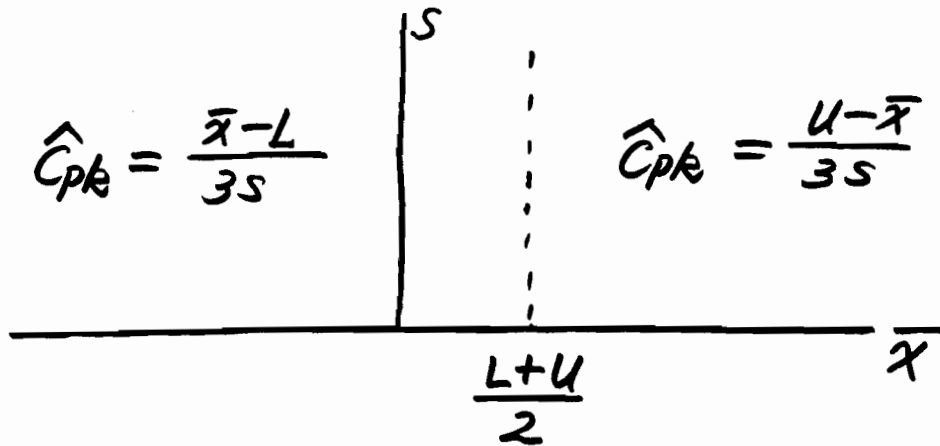


Derivation: x_1, x_2, \dots, x_n iid $N(\mu, \sigma^2)$



$$g(a, b) = \min \left\{ \frac{U-a}{3\sqrt{b}}, \frac{a-L}{3\sqrt{b}} \right\}$$

$$g(\bar{x}, s^2) = \hat{C}_{pk}$$

$\text{Var } g(\bar{x}, s^2)$ can be approximated using Δ method.

Suppose $\mu > \frac{L+U}{2}$. Then

$$\begin{aligned} \text{Var } \hat{C}_{pk} &\approx \left(-\frac{1}{3\sigma}\right)^2 \text{Var}(\bar{x}) \\ &\quad + \left(\frac{U-\mu}{3}\right)^2 \left(-\frac{1}{2}(\sigma^2)^{-\frac{3}{2}}\right)^2 \text{Var}(s^2) \end{aligned}$$

now plug in $\text{Var } \bar{x} = \frac{\sigma^2}{n}$
 $\text{Var}(s^2) = \frac{2\sigma^4}{n-1}$

and simplify to get $\frac{1}{9n} + \frac{\hat{C}_{pk}^2}{2(n-1)}$.

Plug in \hat{C}_{pk} for C_{pk} and take the root and you have a standard error for \hat{C}_{pk} .

§5.3 Another way to characterize process output is through statements of where individual values are likely to be — prediction and tolerance intervals (PI's & TI's)

PI & TI problems are:

X_1, X_2, \dots, X_n iid $F \in \mathcal{F}$
some class of cont \pm dsns
 X_{n+1}

Make a random interval

$$(g_L(\underline{X}), g_U(\underline{X})) = I(\underline{X})$$

from $\underline{X} = (X_1, \dots, X_n)$.

PI problem:

If $P_F [X_{n+1} \in I(\underline{X})] \geq \gamma \quad \forall F \in \mathcal{F}$

then I call $I(\underline{X})$ (for all)

a γ -level PI.

TI problem:

If $P_F [F(g_U(\underline{X})) - F(g_L(\underline{X})) \geq p] \geq \gamma$

$\forall F \in \mathcal{F}$, then I call $I(\underline{X})$ a γ -level TI for a fraction p of the underlying dsn F .

Simplest version of this is where

\mathcal{F} = class of all cont \pm dsns

<u>Interval</u>	<u>Confidence Level Prediction Int.</u>	<u>Confidence Level as TI for fraction p</u>
$(\min X_i, \infty)$	$\frac{n}{n+1}$	$1 - p^n$
$(-\infty, \max X_i)$	$\frac{n}{n+1}$	$1 - p^n$
$(\min X_i, \max X_i)$	$\frac{n-1}{n+1}$	$1 - p^n - n(1-p) \cdot p^{n-1}$

Why?

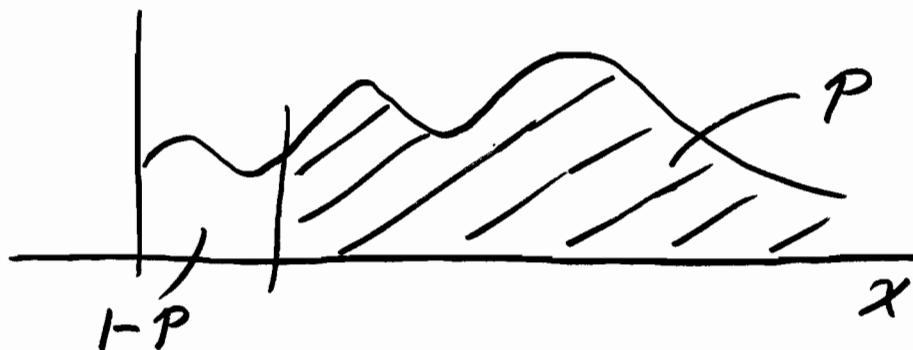
One-Sided Intervals

As PI's:

$$\begin{aligned} & P[(\min X_i, \infty) \text{ doesn't cover } X_{n+1}] \\ &= P[X_{n+1} \text{ is smallest of } X_1, X_2, \dots, X_{n+1}] \\ &= \frac{1}{n+1} \\ &\Rightarrow \text{Confidence level is } \frac{n}{n+1} \text{ for prediction.} \end{aligned}$$

As TI's:

for a fraction P of a ds_n/process/population



$$\begin{aligned} & P[(\min X_i, \infty) \text{ fails to cover a fraction} \\ & \quad P \text{ of the underlying ds}_n] \\ &= P[\text{all of } X_1, X_2, \dots, X_n \text{ exceed the } 1-P \\ & \quad \text{quantile of the underlying ds}_n] \\ &= P^n \Rightarrow \text{Confidence level is } 1-P^n. \end{aligned}$$

Two-Sided Interval

As PI:

$$P[(\min X_i, \max X_i) \text{ doesn't cover } X_{n+1}] \\ = P[X_{n+1} \text{ is the smallest or largest of} \\ X_1, X_2, \dots, X_{n+1}]$$

$$= \frac{2}{n+1} \quad \text{by symmetry}$$

$$\Rightarrow \text{Confidence level is } \frac{n-1}{n+1}.$$

As TI:

$$P_F[F(\max X_i) - F(\min X_i) \geq p]$$

$$= P_F[\max F(X_i) - \min F(X_i) \geq p]$$

and $X \sim F \Rightarrow F(X) \sim \text{Uniform}(0,1)$

-Why? roughly for $t \in (0,1)$ ($U(0,1)$)

$$P[F(X) \leq t] = P[X \leq F^{-1}(t)]$$

$$= F(F^{-1}(t))$$

$$= t$$

i.e., $F(X)$ is $U(0,1)$.

So we want

$$P[\text{range of } n \text{ iid } U(0,1) \text{ r.v.'s} \geq p].$$

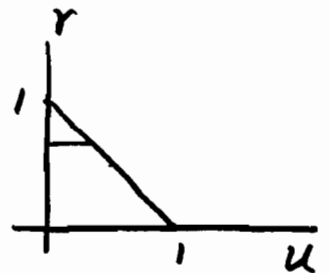
Parallel to material on page 2 of the notes: if U, R are the minimum and range of n iid $U(0,1)$ r.v.'s, their joint pdf is

$$h(u, r) = \begin{cases} n(n-1)r^{n-2} & \text{for } 0 \leq u \leq 1, 0 \leq r \leq 1 \\ & \text{and } 0 \leq u+r \leq 1 \\ 0 & \text{otherwise} \end{cases}$$

For $r \in (0, 1)$,

$$f(r) = \int_0^{1-r} n(n-1)r^{n-2} du$$

$$= n(n-1)r^{n-2}(1-r)$$



$$\text{Hence } P[R \geq p] = \int_p^1 f(r) dr$$

\vdots

$$= 1 - p^n - n(1-p) \cdot p^{n-1}$$

There is also a normal dsm technology for PI's and TI's.

PI stuff X_1, \dots, X_n, X_{n+1} iid $N(\mu, \sigma^2)$

Then, $X_{n+1} - \bar{X} \sim N(0, \sigma^2(1 + \frac{1}{n}))$

$$\left. \begin{array}{l} \frac{(n-1)S^2}{\sigma^2} \sim \chi^2_{n-1} \\ \text{independent.} \end{array} \right\}$$

$$\Rightarrow T = \frac{X_{n+1} - \bar{X}}{S \cdot \sqrt{1 + \frac{1}{n}}}$$

$$= \frac{(X_{n+1} - \bar{X}) / (\sigma \cdot \sqrt{1 + \frac{1}{n}})}{\sqrt{\frac{(n-1)S^2}{\sigma^2} / (n-1)}}$$

$$= \frac{N(0, 1) \text{ r.v.}}{\sqrt{\frac{\chi^2_{n-1} \text{ r.v.}}{n-1}}} \left. \vphantom{\frac{N(0, 1) \text{ r.v.}}{\sqrt{\frac{\chi^2_{n-1} \text{ r.v.}}{n-1}}}} \right\} \text{independent}$$

$$\sim t_{n-1}.$$

So if t^* and t^{**} are such that

$$P[t^* < a \text{ } t_{n-1} \text{ r.v.} < t^{**}] = \gamma$$

$$P[\underbrace{t^* < T < t^{**}}] = \gamma$$

$$\bar{X} + t^* \cdot s \cdot \sqrt{1 + \frac{1}{n}} < X_{n+1} < \bar{X} + t^{**} \cdot s \cdot \sqrt{1 + \frac{1}{n}}$$

i.e., $\bar{X} \pm t \cdot s \cdot \sqrt{1 + \frac{1}{n}}$

are normal theory prediction limits for X_{n+1} .

TI stuff

one-sided TI (one-sided tolerance limit)

— suppose I want a γ level upper tolerance bound for a fraction P of a normal distribution.

Try something of the form

$$\bar{X} + \tau s$$

I want

$$P[\bar{X} + \tau s \geq \underbrace{Q_z(P) = \mu + z_p \cdot \sigma}_{P \text{ quantile of the } dsn}] \geq \gamma$$

Note that

$$\bar{X} + \tau \cdot s \geq \mu + z_p \cdot \sigma$$

$$\text{iff } \bar{X} - \mu - z_p \sigma \geq -\tau \cdot s$$

$$\text{iff } \frac{\bar{X} - \mu - z_p \sigma}{s} \geq -\tau$$

$$\text{iff } \frac{1}{\sqrt{n}} \cdot \frac{\frac{\bar{X} - \mu}{\sigma/\sqrt{n}} - \sqrt{n} z_p}{\frac{s}{\sigma}} \geq -\tau$$

$$\text{iff } \frac{\begin{array}{l} \nearrow \text{a } N(0,1) \text{ r.v.} \\ \searrow \text{independent} \end{array} \frac{-\sqrt{n} z_p}{\sqrt{\frac{\text{a } \chi_{n-1}^2 \text{ r.v.}}{n-1}}} \geq -\sqrt{n} \cdot \tau$$

$$\left\{ \frac{\text{a } N(0,1) \text{ r.v.} - \sqrt{n} z_p}{\sqrt{\frac{\text{a } \chi_{n-1}^2 \text{ r.v.}}{n-1}}} \right\} \text{independent}$$

a noncentral t_{n-1} r.v. with noncentrality parameter $-\sqrt{n} z_p$.

i.e., I want

$-\sqrt{n} \tau = 1-\tau$ quantile of the noncentral $t_{n-1}(-\sqrt{n} z_p)$.

i.e., I want

$$\tau = -\frac{1}{\sqrt{n}} \left(1-r \text{ quantile of } t_{n-1}(-\sqrt{n} z_p) \right)$$

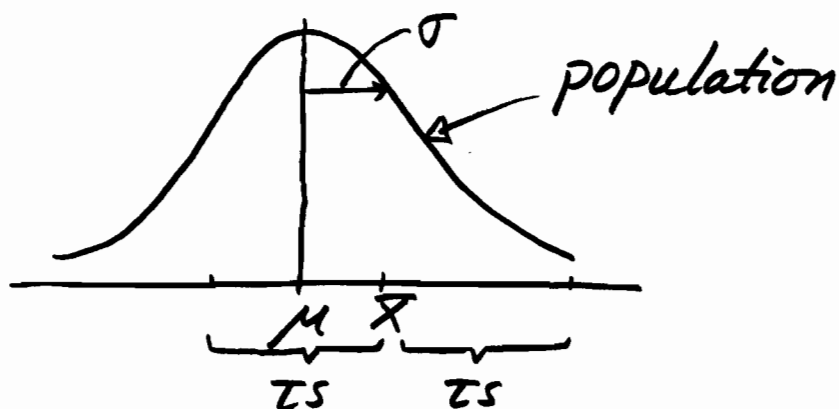
$$= \frac{1}{\sqrt{n}} \cdot (r \text{ quantile of } t_{n-1}(\sqrt{n} z_p))$$

see page 523 of V&J, Table A.9b.

Notes: 1) There exist explicit approximations for τ 's just considered (see problem 4.3 of the notes).

2) There exist two-sided one-sample TIs ($\bar{x} - \tau \cdot s$, $\bar{x} + \tau \cdot s$).

$$P_{\mu, \sigma} \left[\Phi \left(\frac{\bar{x} + \tau \cdot s - \mu}{\sigma} \right) - \Phi \left(\frac{\bar{x} - \tau \cdot s - \mu}{\sigma} \right) \geq p \right] \geq \gamma$$



This is the same as

$$P \left[\Phi \left(\frac{z}{\sqrt{n}} + \tau \cdot \sqrt{\frac{W}{n-1}} \right) - \Phi \left(\frac{z}{\sqrt{n}} - \tau \cdot \sqrt{\frac{W}{n-1}} \right) \geq p \right] \geq \gamma$$

where $z \sim \text{std normal}$ } independent
 $W \sim \chi_{n-1}^2$

— I must select τ to get the desired γ (see page 522 of V&J, Table A.9a).

§5.4. Probabilistic Tolerancing/Error Analysis

Technically this is nothing more than an application of propagation of error (simulation).

Application is to engineering design.

Idea is that in some contexts there are good deterministic models for how an output is a function of several inputs:

$U = g(X, Y, \dots, Z)$
some product quality variable ← properties of the product

First-order Taylor series analysis says for independent inputs

$$\text{Var } U \approx \left(\frac{\partial g}{\partial x}\right)^2 \text{Var } X + \left(\frac{\partial g}{\partial y}\right)^2 \text{Var } Y + \dots + \left(\frac{\partial g}{\partial z}\right)^2 \text{Var } Z$$

where partials are evaluated at (EX, EY, \dots, EZ) .

I can therefore hope to make $\text{Var } U$ small by controlling $\text{Var } X$, $\text{Var } Y$, \dots , $\text{Var } Z$ or by making partials small (possibly by choice of EX , EY , \dots , EZ).

Example 5.9

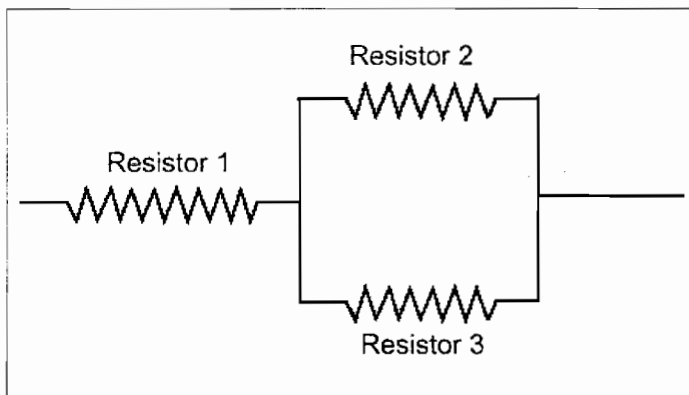
- Nice little tolerance stack-up problem

$$U = Y - X_1 - X_2 - X_3 - X_4$$

$$\sigma_U^2 = 1^2 \sigma_Y^2 + (-1)^2 \sigma_{X_1}^2 + (-1)^2 \sigma_{X_2}^2 + (-1)^2 \sigma_{X_3}^2 + (-1)^2 \sigma_{X_4}^2$$

- U was head space in a carton designed to hold 4 units of product

Example 5.8



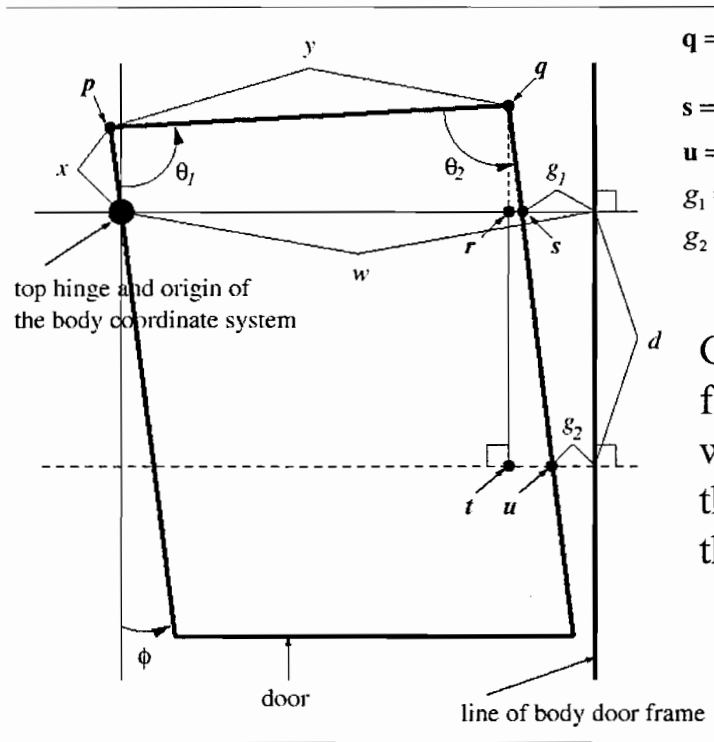
$$R = R_1 + \frac{R_2 R_3}{R_2 + R_3}$$

$$\mu_{R_1} = 100\Omega \text{ and } \mu_{R_2} = \mu_{R_3} = 200\Omega$$

$$\sigma_{R_1} = 2\Omega \text{ and } \sigma_{R_2} = \sigma_{R_3} = 4\Omega$$

What about R ?

Car Door Example



$$\mathbf{p} = (-x \sin \phi, x \cos \phi)$$

$$\mathbf{q} = \mathbf{p} + \left(y \cos \left(\phi + \left(\theta_1 - \frac{\pi}{2} \right) \right), y \sin \left(\phi + \left(\theta_1 - \frac{\pi}{2} \right) \right) \right)$$

$$\mathbf{s} = (q_1 + q_2 \tan(\phi + \theta_1 + \theta_2 - \pi), 0)$$

$$\mathbf{u} = (q_1 + (q_2 + d) \tan(\phi + \theta_1 + \theta_2 - \pi), -d)$$

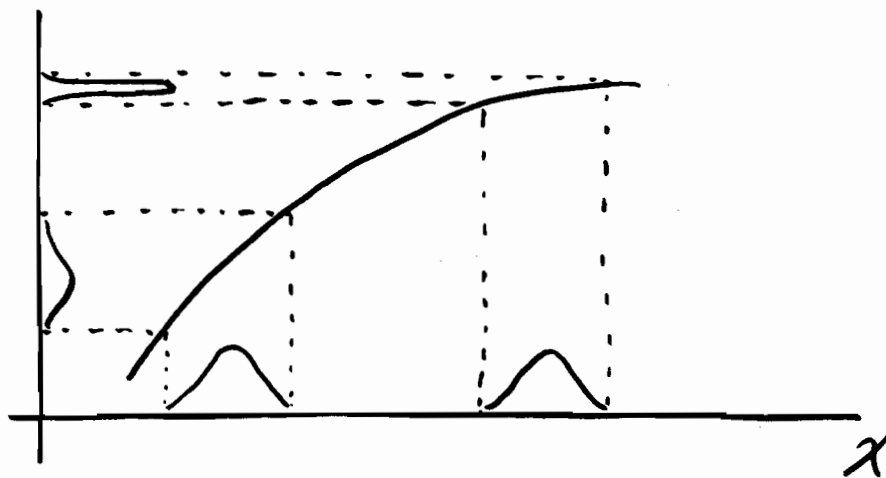
$$g_1 = w - s_1$$

$$g_2 = w - u_1$$

Given nominals and "sigmas" for x, y, w, ϕ, θ_1 and θ_2 what can I say about the the nominals and "sigmas" for the gaps, g_1 and g_2 ?

(Problem 4.12 of the Notes)

$$U = g(x)$$



'Robust' ('Taguchi') product design

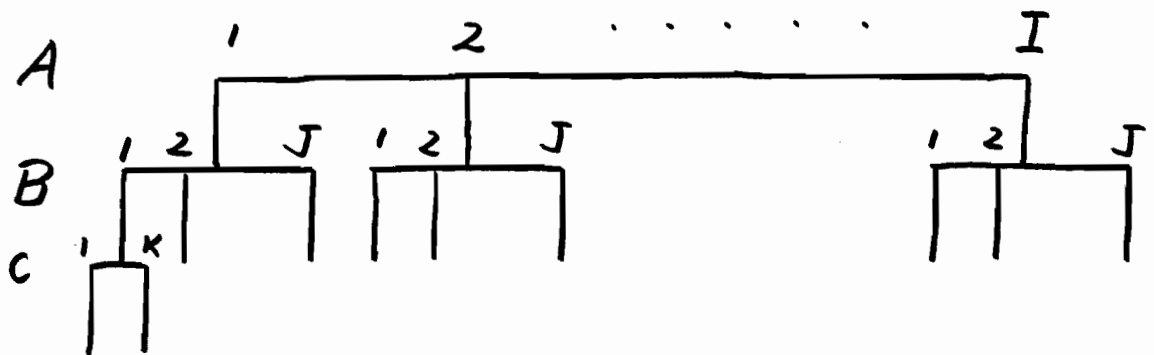
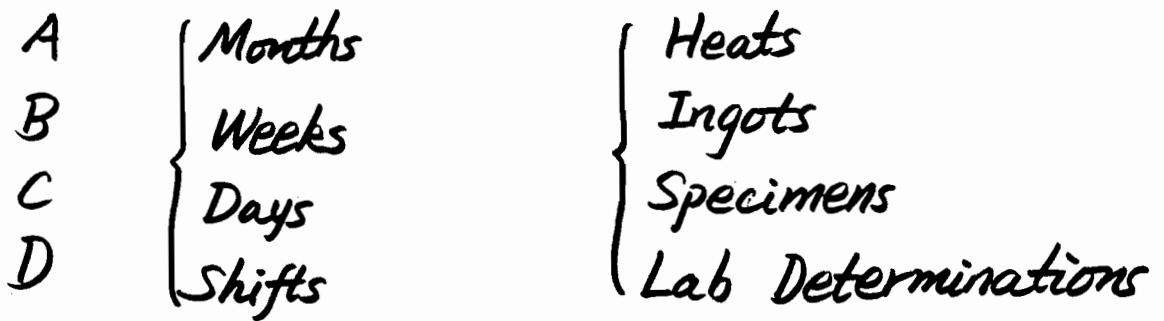
— see problems 4.11 and 4.12 of the notes for 'examples.'

§5.5 of V&J (Ch. 4 of the notes)

Variance Component Analysis in Hierarchical Contexts —

A common structure in industrial contexts is one where levels of A give rise to levels of B, which give rise to levels of C, etc. and one would like to "partition" variability encountered.

E.g.



etc.

Balanced Hierarchical Data

y_{ijk} = observation for the k th level
of C within j th level of B
within the i th level of A

$$y_{ijk} = \mu + \alpha_i + \beta_{ij} + \epsilon_{ijk}$$

for α 's, β 's and ϵ 's independent

$$\alpha_i \sim N(0, \sigma_\alpha^2), \beta_{ij} \sim N(0, \sigma_\beta^2), \epsilon_{ijk} \sim N(0, \sigma^2)$$

For balanced data, estimation of variance components is standard and based on ANOVA SS's and MS's.